


Issue Classification 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/764,283	CHAPMAN, THOMAS R.	
	Examiner	Art Unit	
	Devin Hanan	3745	

ISSUE CLASSIFICATION									
ORIGINAL				CROSS REFERENCE(S)					
CLASS	SUBCLASS			CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)				
416	185			415	206				
INTERNATIONAL CLASSIFICATION									
F	0	I	D	5/22					
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<i>Devin Hanan 4/14/2006</i> Devin Hanan 4/14/2006 (Assistant Examiner) (Date)				<i>Edward K. Look 4/12/06</i> EDWARD K. LOOK SUPERVISORY PATENT EXAMINER TECHNOLOGY CENTER 3700 (Patent Examiner) (Date)				Total Claims Allowed: 35	
<i>McCooper 4/20/06</i> (Legal Instruments Examiner) (Date)								O.G. Print Claim(s) 1	O.G. Print Fig. 2

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant		<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R.1.47	
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